IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney Docket No. 50169/105/ENPO

J. Lee

Group Art Unit:

Examiner:

In re patent application Of

Wallace T.Y. TANG

Serial No. 08/401,229

Filed:

March 9, 1995

IN-SITU REAL-TIME N TECHNIQUE AND APPARATUS FOR ENDPOINT

DETECTION OF THIN FILMS DERING CHEMICAL/MECHANICAL POLISHING

PLANARIZATION

TRANSMITTAL

RECEIVED

2501

Assistant Commissioner for Patents Washington, D.C. 20231

JAN 2 2 1997

Sir:

For:

GROUP 2500

Transmitted herewith is an Amendment in the above-captioned application. The fee has been calculated as shown below. (Small entity fees indicated in parentheses.)

CLAIMS AS AMENDED						
(1)	(2)	(3)	(4)	(5)	(6)	(7)
	Claims Remaining After Amendment		Highest Number Previously Paid For	Extra Claims	Rate	Fee
Total Claims	56	_	22	34	22.00	374.00
(Small Entity)					(11.00)	
Independent claims	12	-	7	6	80.00	240.00
(Small Entity)					(40.00)	
Multiple Dependent		_			260.00	
(Small Entity)					(130.00)	
Extension of Time	One Month		Two Months	Three Months		
Fee	\$110		\$390	\$930		
(Small Entity)	(\$55)		(\$195)	(\$465)		
Total						\$614.00

A check in the amount of the above Total Fee is attached. This amount is believed to be correct; however, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 19-0741.

Respectfully submitted,

December 9, 1996 Date:

Stephen B. Maebius

Registration No. 35,264

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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney Docket No. 50169/105/ENPC

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DEC - 9 1996

In re patent application of

Wallage Y.Y. TANG

Group Art Unit: 2501

Examiner: J. Lee

Serial No. 08/401,229

Filed: March 9, 1995

For IN-SITU

IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR ENDPOINT DETECTION OF THIN FILMS DURING CHEMICAL/MECHANICAL POLISHING PLANARIZATION ECENTED

AMENDMENT AND REQUEST FOR RECONSIDERATION

UNDER 37 C.F.R. § 1.111

GROUP 2500

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

In response to the outstanding Office Action mailed on September 9, 1996, please amend the above-identified application as follows:

IN THE CLAIMS

Please cancel claims 36-38.

Please add the following claims:

A chemical mechanical polisher for planarizing a film on a substrate comprising at least one light source that illuminates at least one section of the film on the substrate to create at least one reflected light signal received by a photodetector positioned in close proximity to the reflected light signal, which converts the reflected light signal into an electrical signal and transmits the electrical signal to an electrical slip ring, said electrical slip ring uncoupling the electrical signal from rotation and being operably connected to an analyzer that analyzes the electrical signal to monitor the progress of planarization.